Virtual Pepper-Pot Technique for 4D Phase Space Studies.

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Screen

.

0.2

0.5

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Movable slit

(reference screen)

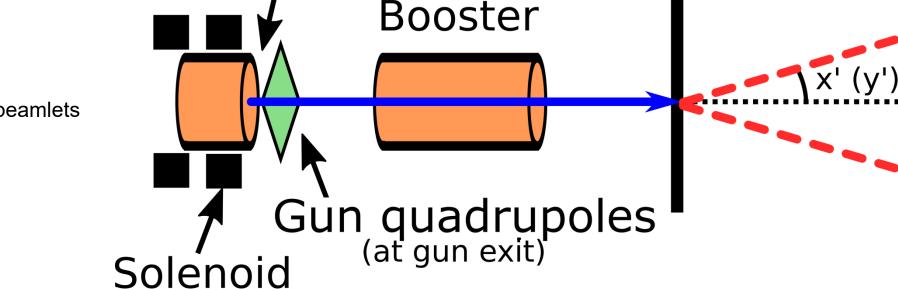
Introduction

There are ongoing beam coupling studies at the Photo Injector Test facility at DESY in Zeuthen (PITZ). Electron beam asymetries have been observed and gun quadrupoles are installed to correct them. A 4D phase space characterization is required to understand the asymmetries in detail

The Virtual-Pepper Pot (VPP) technique is an analysis technique for measurement of 4D transverse phase space and 4D projected emittance of space-charge dominated electron beams. A step called beamlet crossing is crucial in the analysis. Images of beamlets from single slit scan in both horizontal and vertical direction are combined. Each generated image by beamlet crossing corresponds and resembles an image of a single aperture.

Experimental setup

- Sigle slit scan standard method at PITZ
- Laser pulse: 1.2 mm diameter, FWHM ~11 ps
- > 1,6 cell electron gun \rightarrow 6,5 MeV/c
- ➢ Gun solenoid
- ➢ Gun quadupoles: 1 normal + 1 skew
- > Booster \rightarrow 22,3 MeV/c at exit
- \succ First station:
 - > Slit: 1.0 mm thick, 10 μ m opening
 - > Screen \rightarrow reference image
- Vacuum drift 3.13 m
- \succ Second station:
 - Beamlet collector screen
- Beamlet
- Low charge Emittance dominated
- Low signal to noise ratio
- \succ Each beamlet \rightarrow slice of 2D phase space
- \rightarrow 2D phase space \rightarrow reconstructed from all beamlets

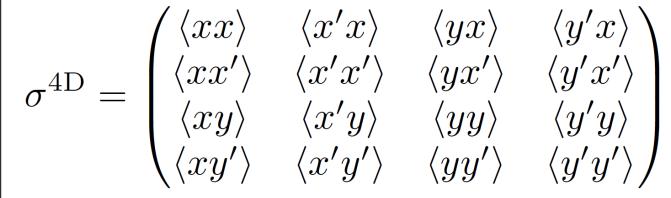


RF gun

Virtual-Pepper Pot

Theory

4D transverse beam matrix A main theoretical tool to describe the 4D beam dynamics is the 4D transverse beam matrix



with elements *<uu>* and *<uv>* representing a variance of *u* and a covariance between *u* and *v* respectively.

Emittance and emittance invariant

The projected horizontal emittance (and analogycally for vertical emittance) is defined as

$$\epsilon_{x,\text{scaled,normalized}} = f_{\text{scaling}} \beta \gamma \sqrt{\langle x^2 \rangle \langle x'^2 \rangle - \langle xx' \rangle^2}$$

with relativistic factors product $\beta\gamma$ and scaling factor defined as the ratio of the full beam size to the reconstructed beam size

$$f_{x,\text{scaling}} = \frac{\sigma_{x,\text{fullbeam}}}{\sigma_{x,\text{slitscan}}}$$

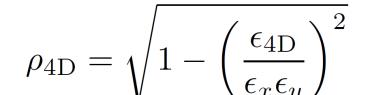
The 4D emittance is defined as

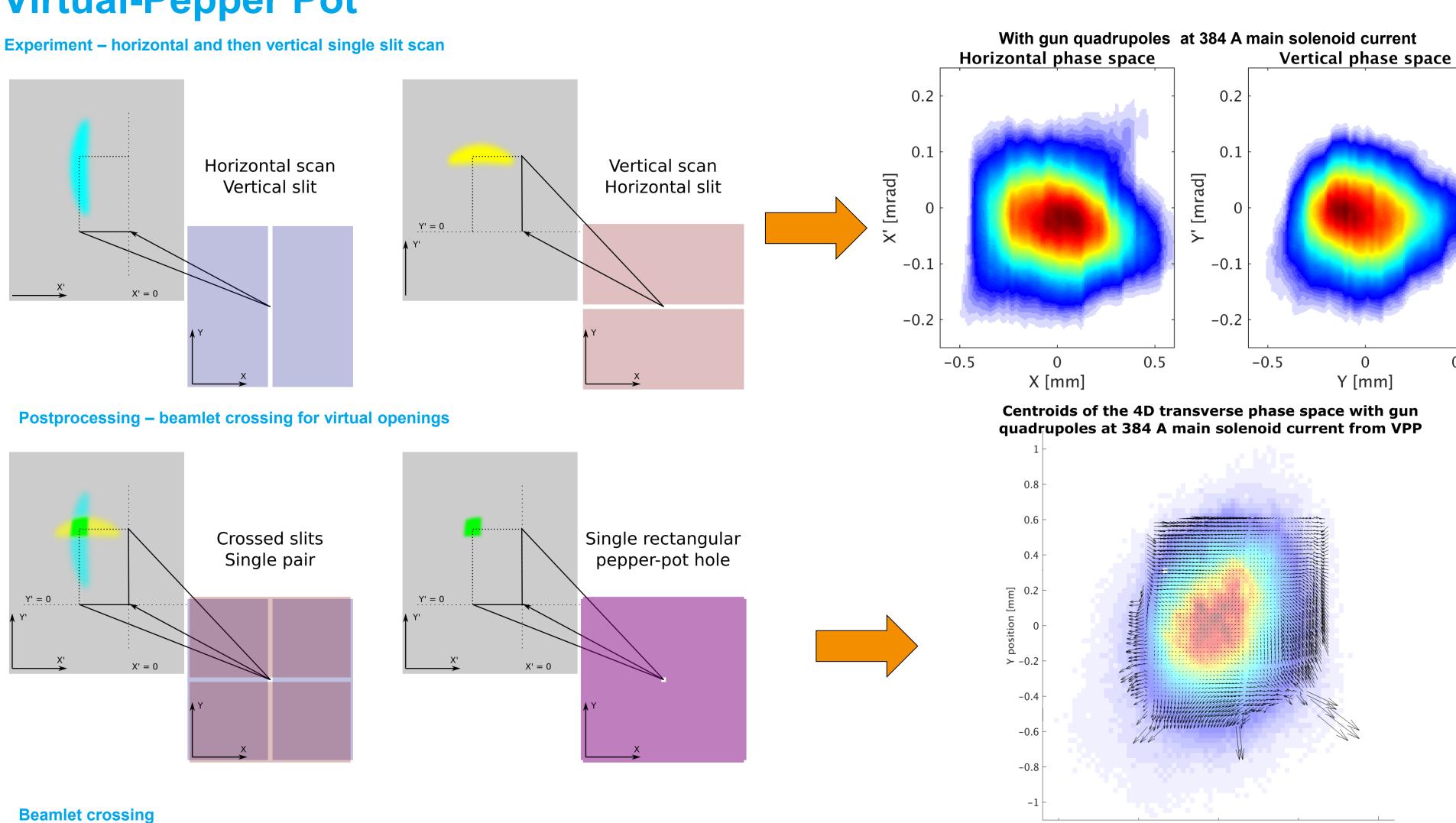
$$\epsilon_{4D,scaled,normalized} = f_{x,scaling} f_{y,scaling} (\beta \gamma)^2 \sqrt{\det(\sigma^{4D})}$$

A transverse emittance invariant is defined as

 $I_2^{(2)} = \epsilon_x^2 + \epsilon_y^2 + 2 \begin{vmatrix} \langle xy \rangle & \langle x'y \rangle \\ \langle xy' \rangle & \langle x'y' \rangle \end{vmatrix}$ ^[2]

X-Y correlation and coupling factors A correlation value between horizontal phase space and vertical phase space is introduced as





Horizontal scan

beamlet image

Vertical scan beamlet image

Crossed VPP beamlet image



For any virtually crossed slit pair only a beam charge Q₀ passes through to the second screen. During the actual slit scan the Q₀ charge is mixed with the rest of the passing charge. The beamlet crossing step has to separate Q₀ of a pair of slits as much as possible. The pixel-wise minimum is the operation chosen for beamlet crossing

-1

-0.5

0

X position [mm]

0.5

Its value ranges between 0 (no correlation) and 1 (fully correlated) in analogy to Pearson's coefficient.

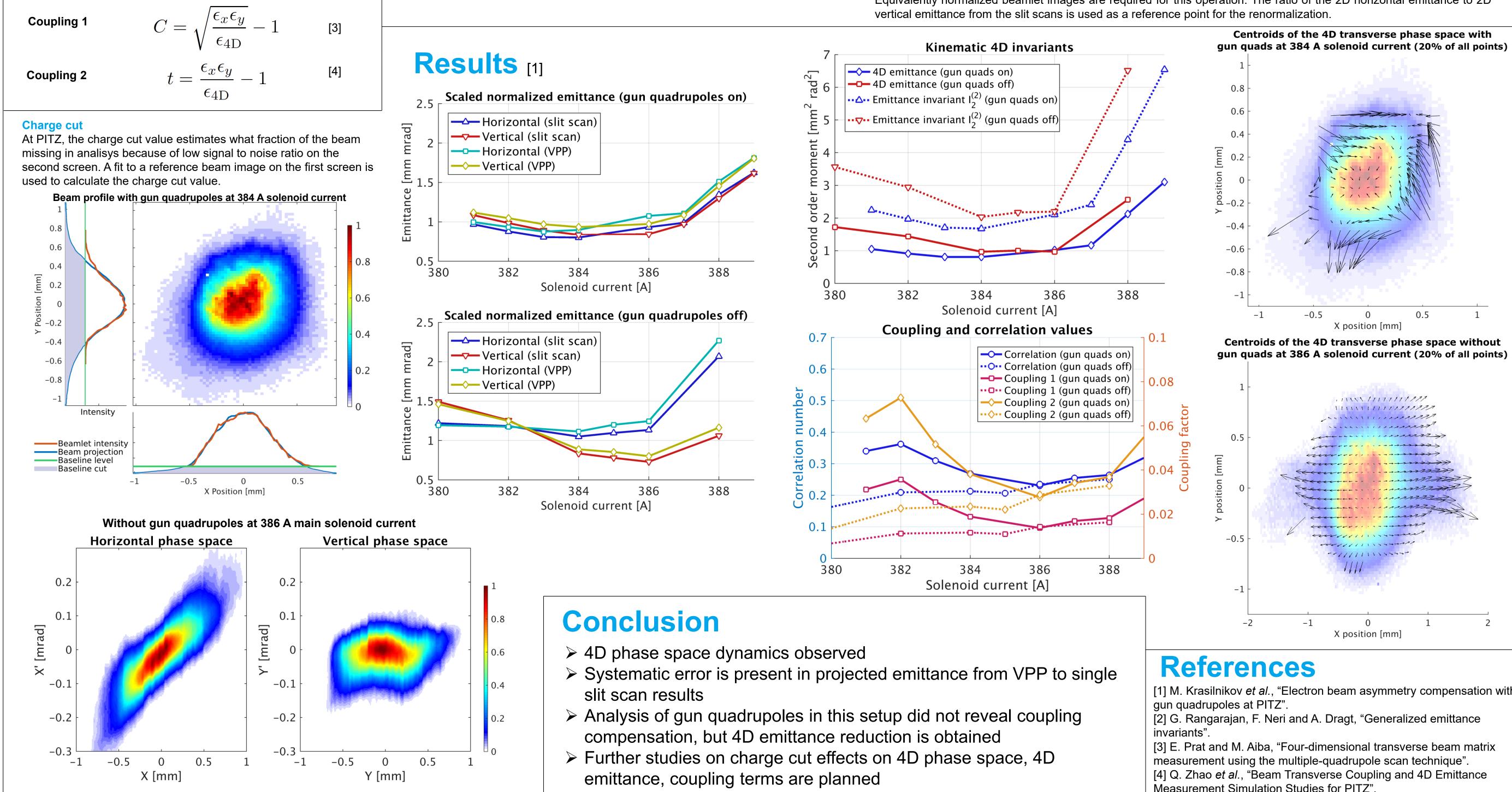
Two coupling factors are shown for comparison.

Coupling 1



$Q_{\text{cross}} = \min(Q_x, Q_y) = Q_0 + \min(Q_{fx}, Q_{fy})$

For any pair of beamlet images there are distinct Q_{fx} and Q_{fy}, referred to as foreign charges, of the corresponding vertical and horizontal slit image. The pixel-wise minimum operation minimizes the foreign charge for the crossing. Equivalently normalized beamlet images are required for this operation. The ratio of the 2D horizontal emittance to 2D vertical emittance from the slit scans is used as a reference point for the renormalization.



[1] M. Krasilnikov et al., "Electron beam asymmetry compensation with

Measurement Simulation Studies for PITZ".

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